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Trapped ions

Long coherence times $(T_2^* > 50 s) \rightarrow$ excellent quantum memory

Proven high-fidelity quantum operations \rightarrow fault-tolerance

two-qubit gate error ≈ 10⁻³ (100 µs gate duration)

fast two-qubit gate error $\approx 2.5 \cdot 10^{-3}$ (1.6 µs gate duration)

Quantum

charge coupled

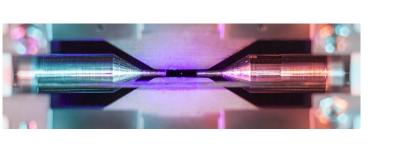
device

Identical qubits \rightarrow scalability

• readout error $\approx 5 \cdot 10^{-4}$

• state preparation error $\approx 2 \cdot 10^{-4}$

• single-qubit gate error ≈ 10⁻⁶







Imperial College London

University of Sussex

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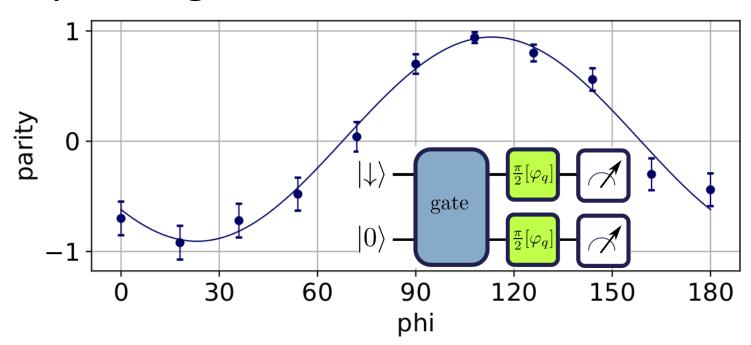
Southampton

Control system

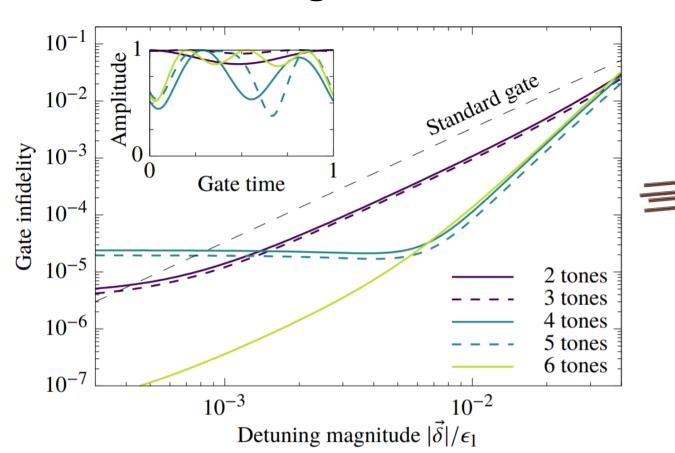


Robust entangling gates

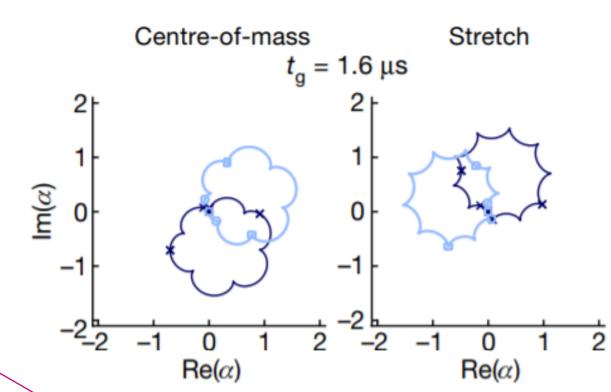








Fast two-qubit entangling gates $t_a = 1.6 \; \mu s$







Advanced ion traps

Traps for microwave-driven quantum logic gates

Macroscopic traps with integrated optical cavity

Vetworked

Information

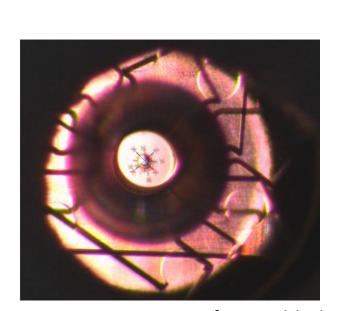
Technologies

Quantum



OXFORD NICS

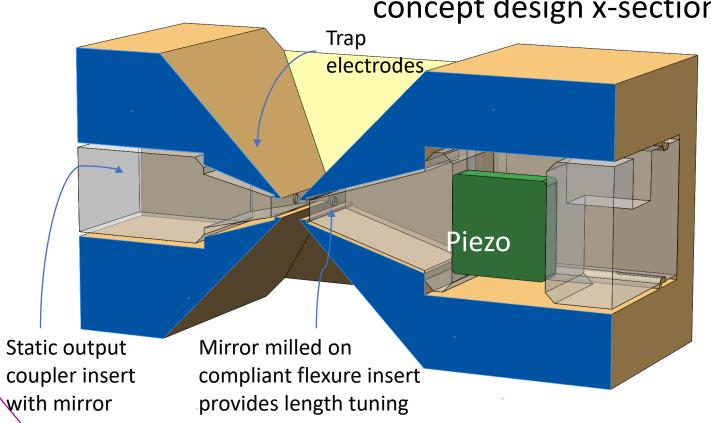
Quick turnaround cryogenic testbed



Microfabricated traps with integrated optical cavity

Microscope image of assembled microcavity

1-DOF cavity trap concept design x-section



ColdQuanta UK

OXFORD HIGHQ







Quantum networking

Two-node networking experiment remote entanglement with F=0.94 at 180/sec

Quantum

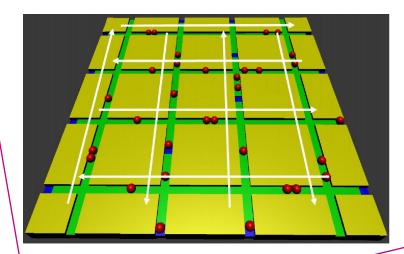
networks

example applications:

- device-independent QKD
- blind quantum computing
- entanglement distillation across nodes

Large scale quantum

Shuttling ions for Noisy-Intermediate-Scale-



computation

Quantum (NISQ) devices